

Radiation hardness of small-pitch 3D pixel sensors up to HL-LHC fluences

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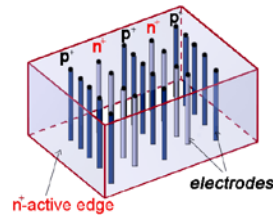
IFAE Barcelona

Maria Manna, Giulio Pellegrini, David Quirion

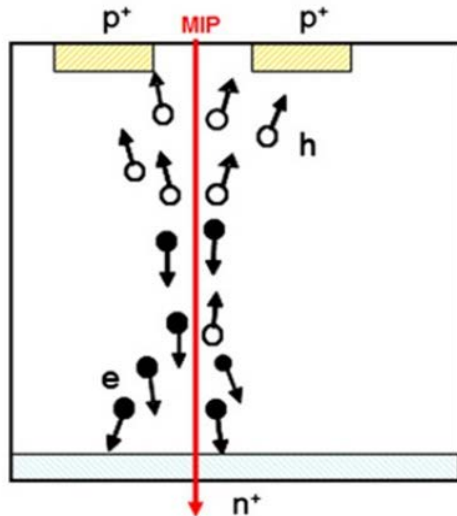
CNM-IMB-CSIC Barcelona

TIPP, Beijing, 24 May 2017

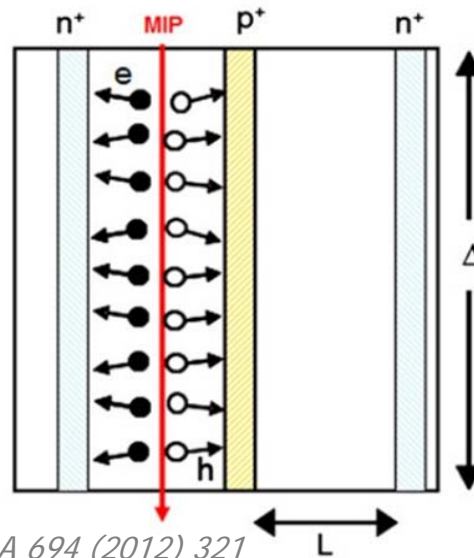
3D Detector Principle



Planar Technology



3D Technology



C. Da Via et al., NIM A 694 (2012) 321

Radiation-hard and active/slim-edge technology

Advantages

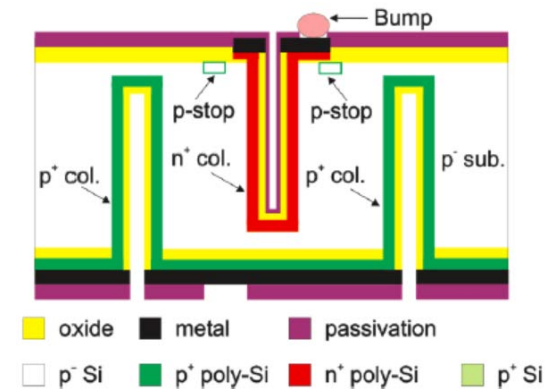
- Electrode distance decoupled from sensitive detector thickness
 - lower $V_{\text{depletion}}$
 - less power dissipation, cooling
 - smaller drift distance
 - faster charge collection
 - less trapping
- Active or slim edges are natural feature of 3D technology

Challenges

- Complex production process
 - long production time
 - lower yields
 - higher costs
- Higher capacitance
 - higher noise
- Non-uniform response from 3D columns and low-field regions
 - small efficiency loss at 0°

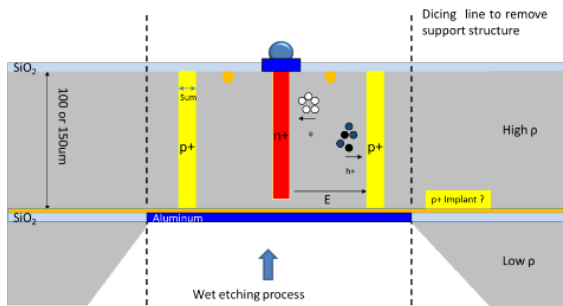
Different 3D Technologies

- Double sided (available at CNM)
 - IBL/AFP-proven technology
 - No handling wafers needed
→ thickness limited to $\geq 200 \mu\text{m}$ and wafers to 4"
 - 3D columns $\sim 8 \mu\text{m}$ diameter
- Single sided (available at FBK, SINTEF, CNM)
 - On handling wafer (SOI or Si-Si bonding)
→ 6" possible (FBK, SINTEF)
 - Active thickness range 50-150 μm being explored
 - Narrow 3D columns $\sim 5 \mu\text{m}$ possible



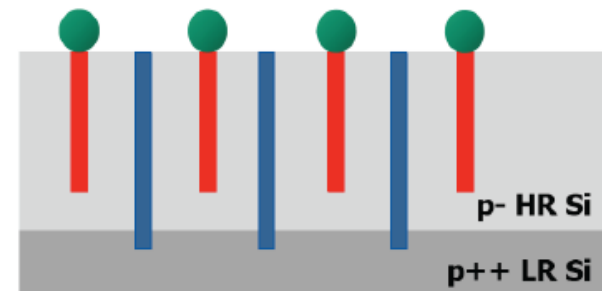
Double-sided

G. Pellegrini, CNM



SOI

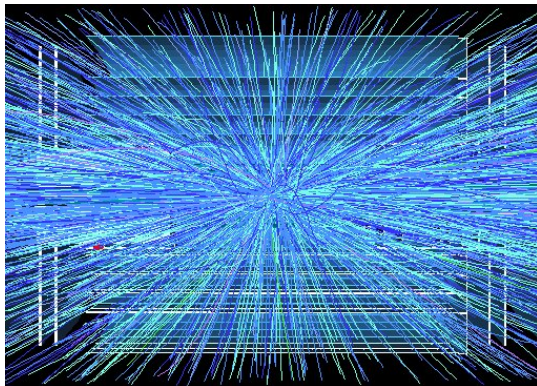
G. Pellegrini, CNM



Si-Si bonding

M. Boscardin, FBK

Applications of 3D Silicon Pixel Detectors



- **ATLAS IBL**

See talk by D. Fares

- 25% 3D FEI4 detectors (CNM+FBK sensors)
- Running since June 2015

- **ATLAS Forward Proton (AFP)**

S. Grinstein et al.,
JINST 12 (2017) C01086

- CNM sensors, 3D pixel modules produced by IFAE
- Running in LHC since March 2016, upgraded in March 2017

- **CMS-TOTEM PPS**

- CNM sensors
- Installed in March 2017

- **HL-LHC pixel detectors**

This talk

- Possible installation 2024, sensor qualification for Pixel TDRs 2017
- **Radiation hardness:** $1\text{--}2 \times 10^{16} \text{ n}_{\text{eq}}/\text{cm}^2$ required
- **Reduced pixel size:** $50 \times 50 \text{ }\mu\text{m}^2$ or $25 \times 100 \text{ }\mu\text{m}^2$
- 3D promising candidate for innermost layer(s)

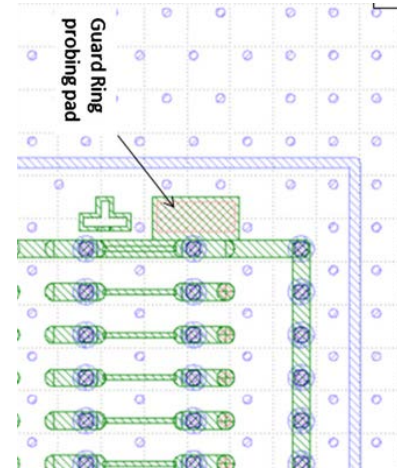
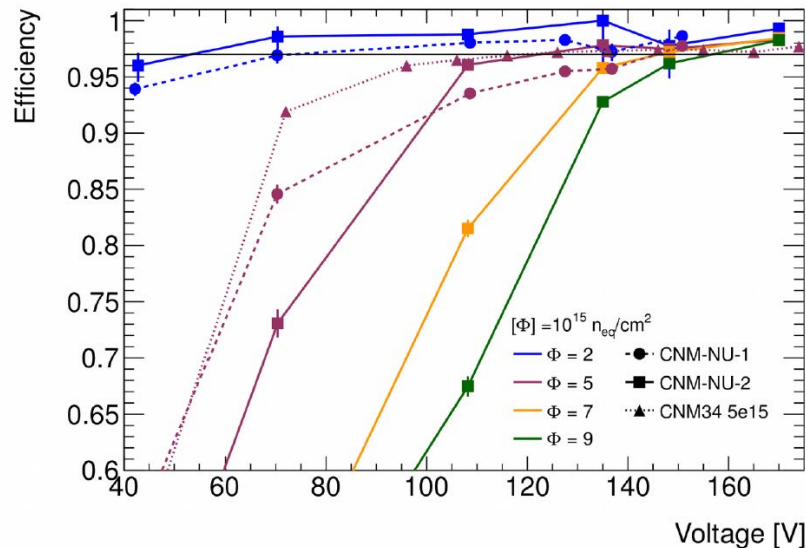
State of the Art: IBL/AFP Generation

- 230 μm thick sensors by CNM and FBK (double-sided)
- FEI4s: $50 \times 250 \mu\text{m}^2$ 2E, 67 μm inter-el. distance
- Radiation hardness up to $5 \times 10^{15} \text{ n}_{\text{eq}}/\text{cm}^2$ established (IBL)
- Explored limits further with irradiations up to HL-LHC fluences
 - At $9.4 \times 10^{15} \text{ n}_{\text{eq}}/\text{cm}^2$: 97.8% efficiency at 170 V!
 - Power dissipation 15 mW/cm² at $1 \times 10^{16} \text{ n}_{\text{eq}}/\text{cm}^2$ and -25°C

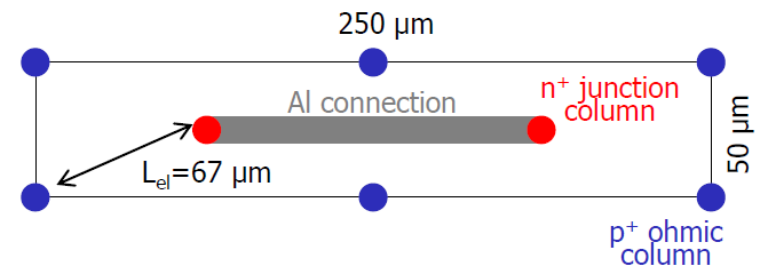
→ **Good performance at HL-LHC fluences even for existing 3D generation**

J. Lange et al., 2016 JINST 11 C11024

p-irradiated FEI4, 0° tilt

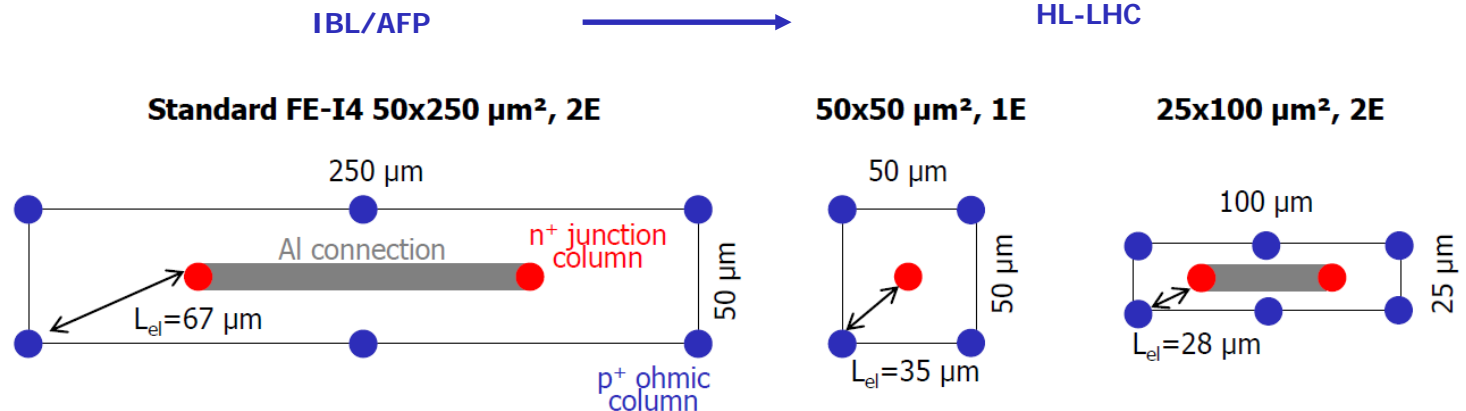
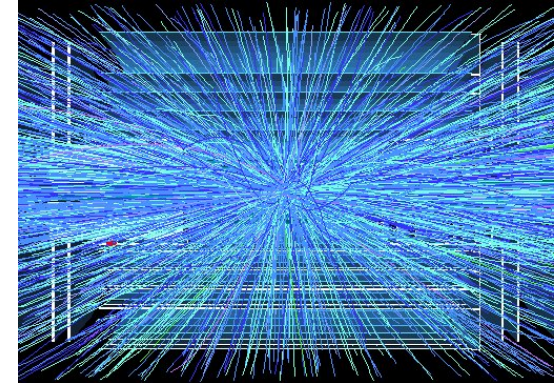


Standard FE-I4 $50 \times 250 \mu\text{m}^2$, 2E

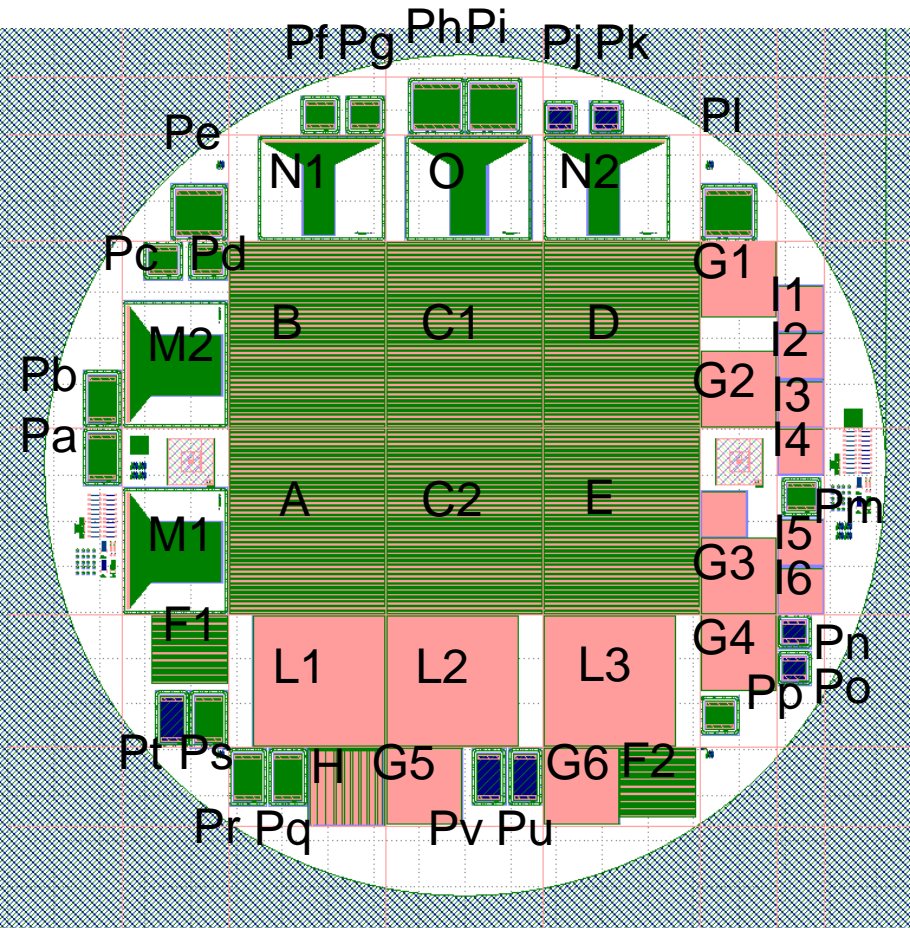


Development of HL-LHC 3D Pixel Detectors

- **Radiation hardness:** $1\text{-}2 \times 10^{16} \text{ n}_{\text{eq}}/\text{cm}^2$ required
- **Reduced pixel size due to occupancy:** $50 \times 50 \text{ }\mu\text{m}^2$ or $25 \times 100 \text{ }\mu\text{m}^2$
 - RD53 readout chip under development
- **Reduced 3D inter-electrode distance L_{el}**
 - less trapping, V_{dep}
 - more radiation hard
 - (but higher C_{det} and more dead material)
- Possibly **reduced thickness** (75-150 μm single-sided)
 - Lower occupancy, I_{leak} , C_{det} (but also lower signal)
 - But here only 230 μm studied



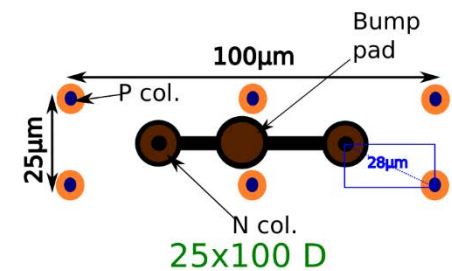
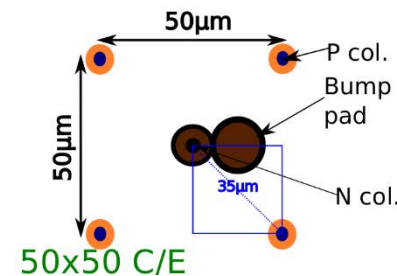
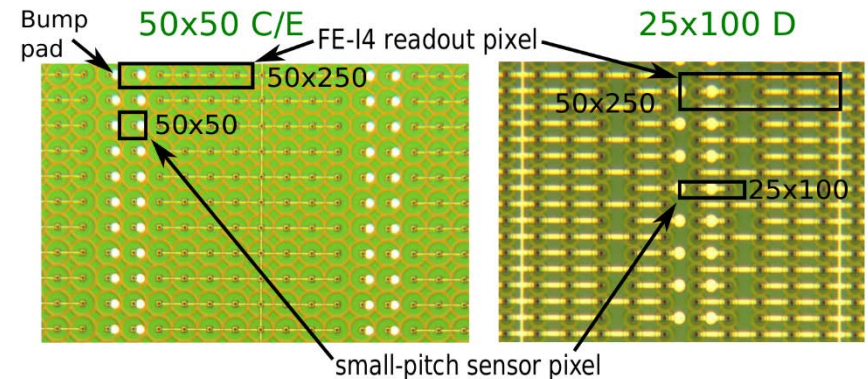
First Small-Pixel CNM Run for HL-LHC



D. Vázquez Furelos et al., 2017 JINST 12 C01026

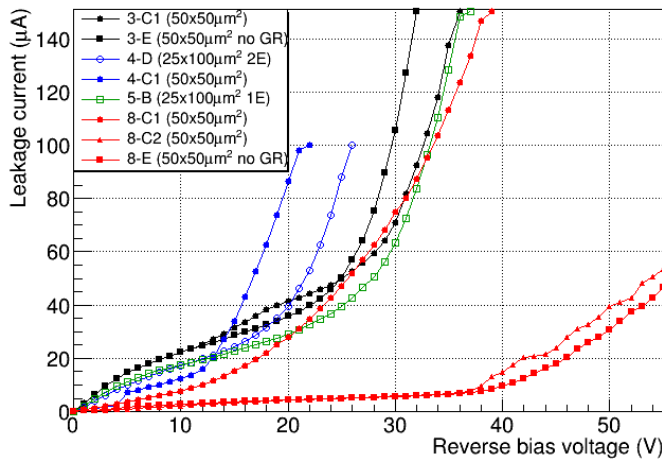
J. Lange et al., 2016 JINST 11 C11024

- Run 7781 finished in Dec 2015
- 5x 4" wafers, p-type, 230 μm double-sided, non-fully-passing-through columns (a la IBL)
- Increased aspect ratio 26:1 (column diameter 8 μm)
- First time small pixel size $25 \times 100 + 50 \times 50 \mu\text{m}^2$** (folded into FEI4 and FEI3 geometries)
- Also strips and diodes down to $25 \times 25 \mu\text{m}^2$ 3D unit cell



Sample Characterisations

Pixel IV

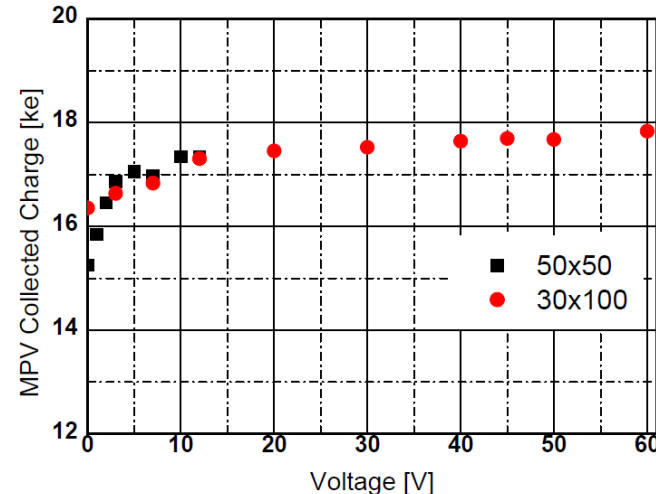


Pixel Geom.	C/el. [fF] (*)	C/pixel [fF] (*)	Noise [e]
25x100 2E	42	84	160
50x50 1E	37	37	105-140

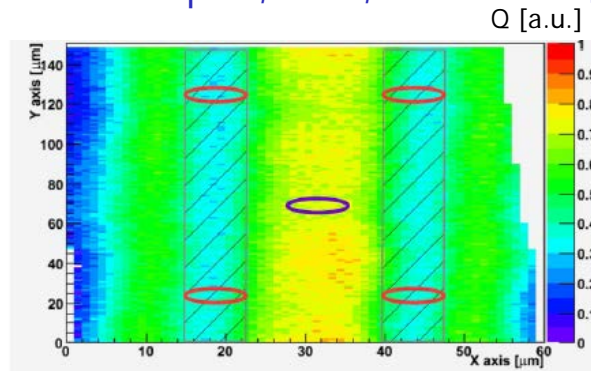
(*) from pad diodes

D. Vázquez Furelos et al.,
2017 JINST 12 C01026

Strips charge collection (unirr.)



Strips laser scan
25x100 μm^2 , 1e16, 150 V



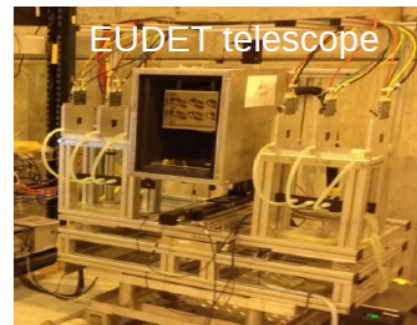
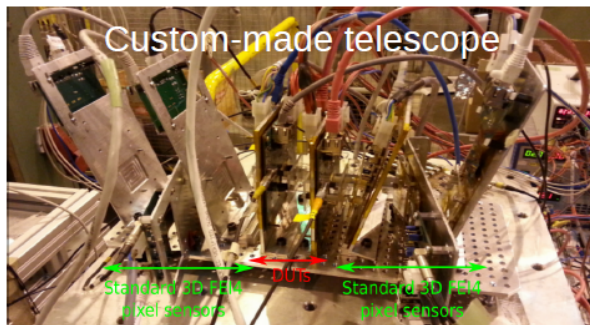
L. Simon

- Pixel devices bump-bonded and assembled at IFAE
- IVs
 - $V_{BD} \sim 15-40 \text{ V}$
 - Improved in new productions after CNM process optimization
S. Grinstein et al., JINST 12 (2017) C01086
- $C < 100 \text{ fF/pixel}$ (within RD53 limit)
- Noise 100-160 e similar to standard 3D FEI4s
- Sr90 source scans on pixels
 - Similar charge as in standard FEI4s
- Sr90 and laser scans on strips
 - 17 ke charge as expected for both 50x50 μm^2 and 30x100 μm^2 (unirr.)
 - Almost full charge even at 0-2 V
 \rightarrow low V_{dep} due to low L_{el}
 - Uniform even after 1e16 n_{eq}/cm^2
 - Measurements up to 2e16 n_{eq}/cm^2 in progress

Beam Tests and Irradiations

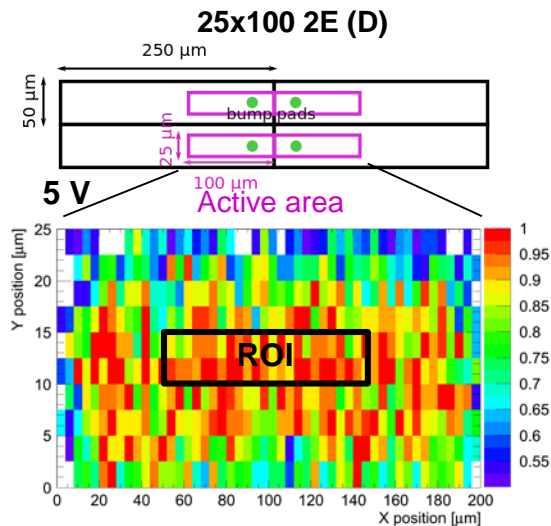
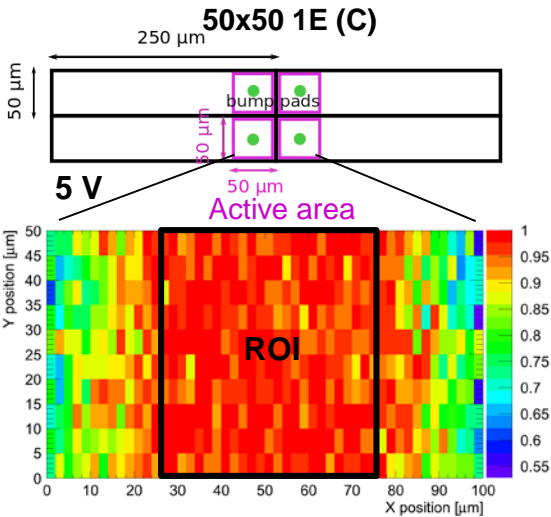
- Irradiation at KIT (uniform) and PS IRRAD (non-uniform)
- Beam tests at CERN SPS H6, 120 GeV pions

Beam Test period	Telescope	Reconstruction framework	Sensor geometry (μm^2)	Irradiation ($n_{\text{eq}}/\text{cm}^2$)
May 2016	Custom-made 3D FEI4	Judith	50x50 + 25x100	Not irradiated
Nov 2016	EUDET	EUTelescope + TBmon2	50x50 + 50x50	5e15 (uniformly 23 MeV p^+ - KIT)
Sept 2016	EUDET	EUTelescope + TBmon2	50x50	1.4e16 (non uniformly 23 GeV p^+ - CERN PS)



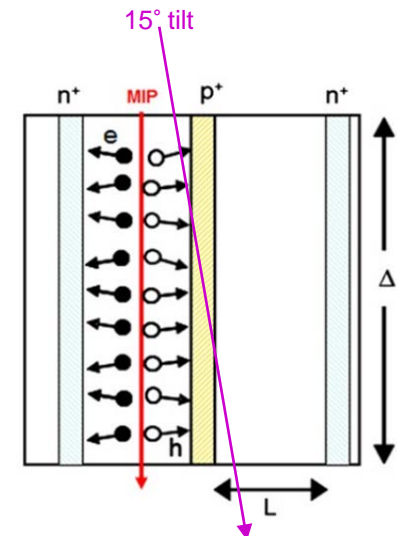
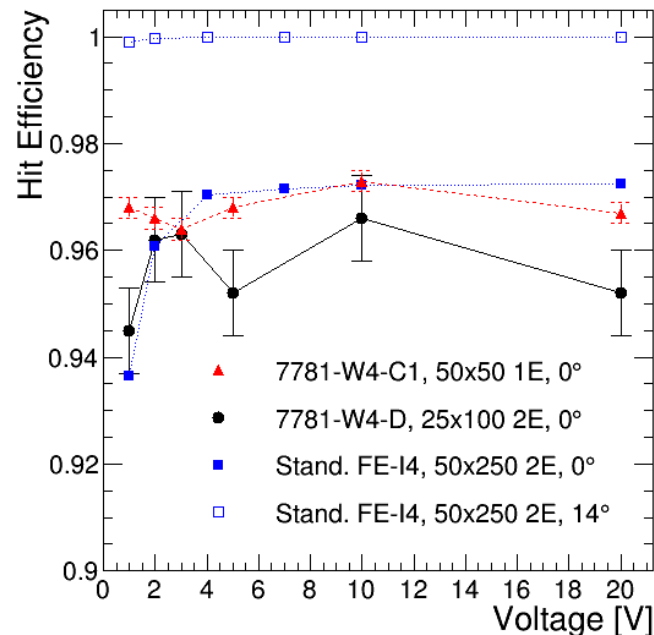
Efficiency before Irradiation

In-Pixel Efficiency (0° tilt)

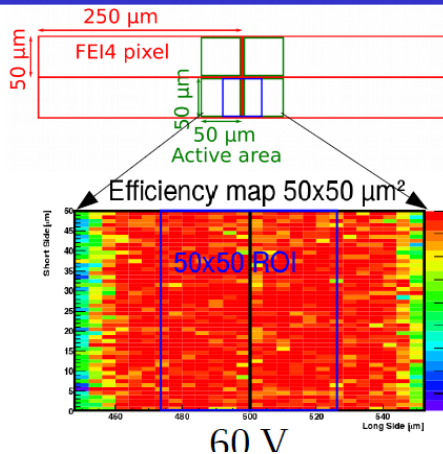


- Select ROI within active region
→ avoid inactive area + telescope smearing
- Efficiency in ROI
 - 97% already from 1 V at 0°: very early depleted due to small electrode distance
 - Improvable by tilting: avoids hitting only low-efficiency regions

J. Lange et al., 2016 JINST 11 C11024

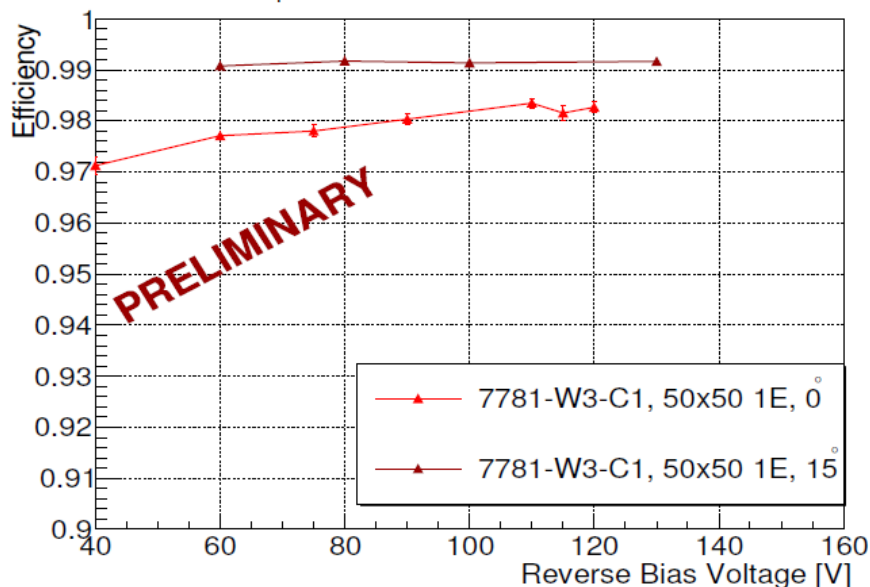


Uniform Irradiation to $5e15 \text{ n}_{eq}/\text{cm}^2$

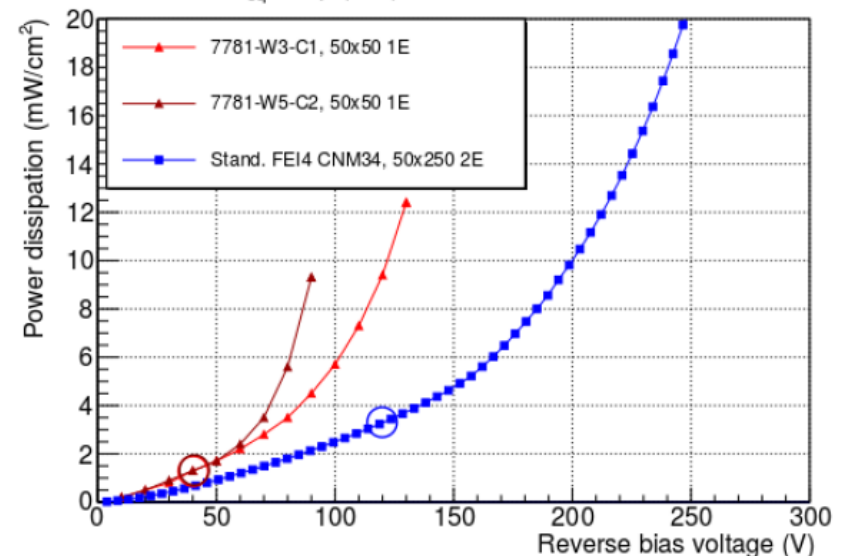


- 2 3D pixel devices of $50 \times 50 \mu\text{m}^2$
- Irradiated uniformly to $5e15 \text{ n}_{eq}/\text{cm}^2$ at KIT
- Already 97% efficiency at 40 V (0° tilt)!
- Compare to standard IBL/AFP FEI4: 120 V
- Improves to 99% at 15° tilt
- Low $V_{op} \rightarrow$ advantage for power dissipation
- $1.5 \text{ mW}/\text{cm}^2$

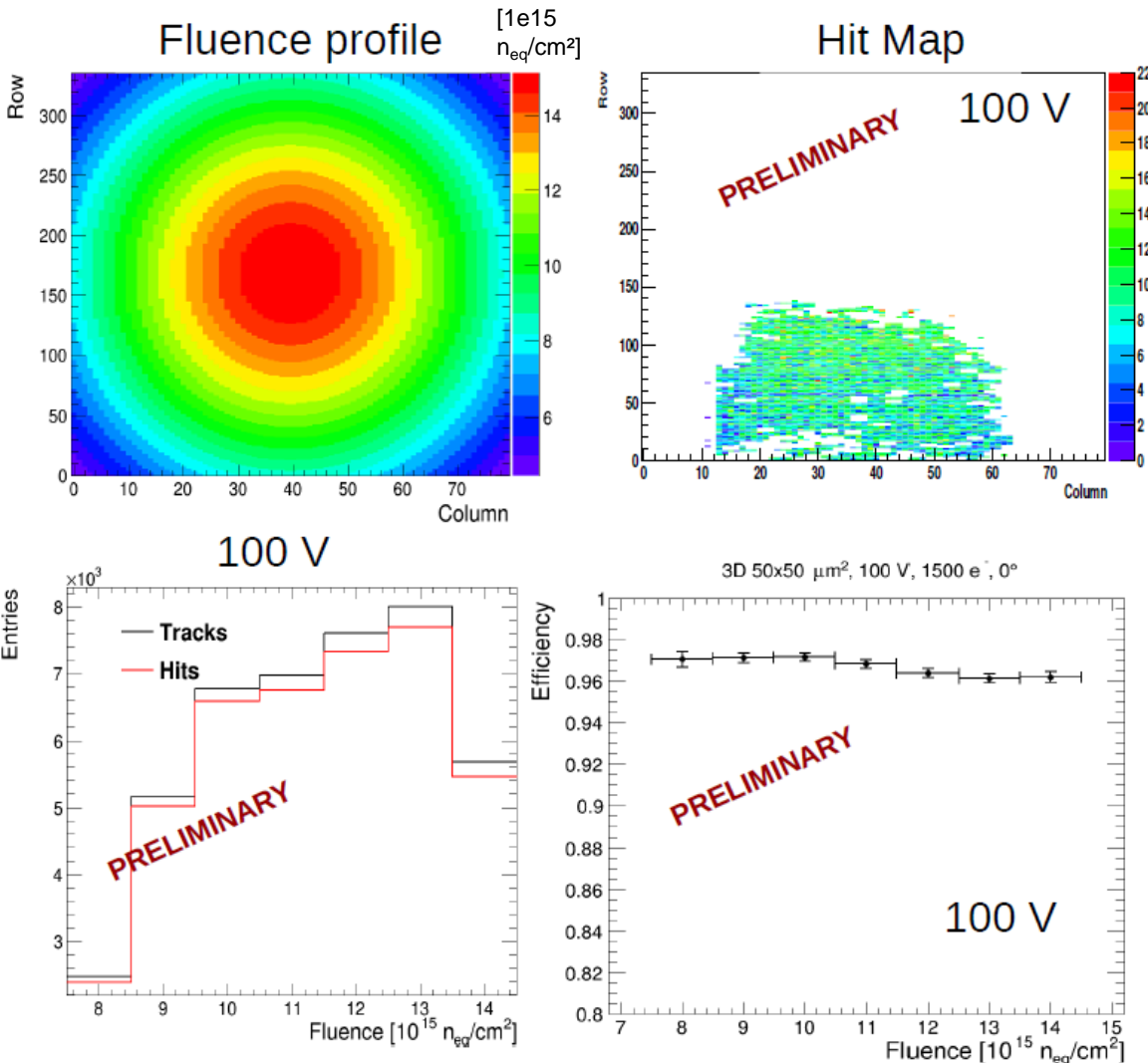
$5e15 \text{ n}_{eq}/\text{cm}^2 \text{p}$ (KIT), thr. 1 ke^- , 10ToT@20ke



$5e15 \text{ n}_{eq}/\text{cm}^2 \text{p}$ (KIT), -25°C , 1 week@RT anneal.

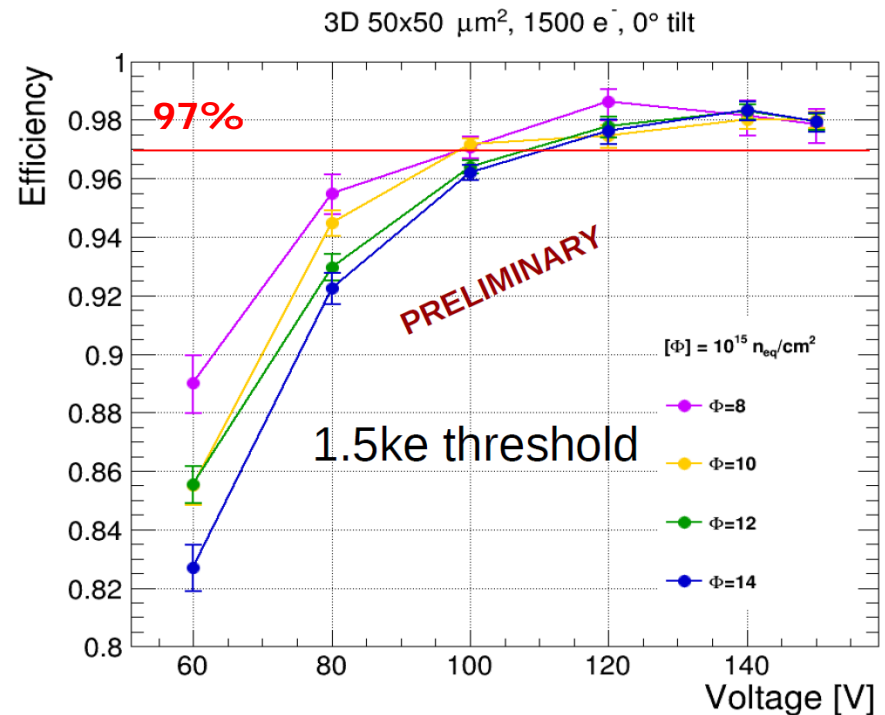
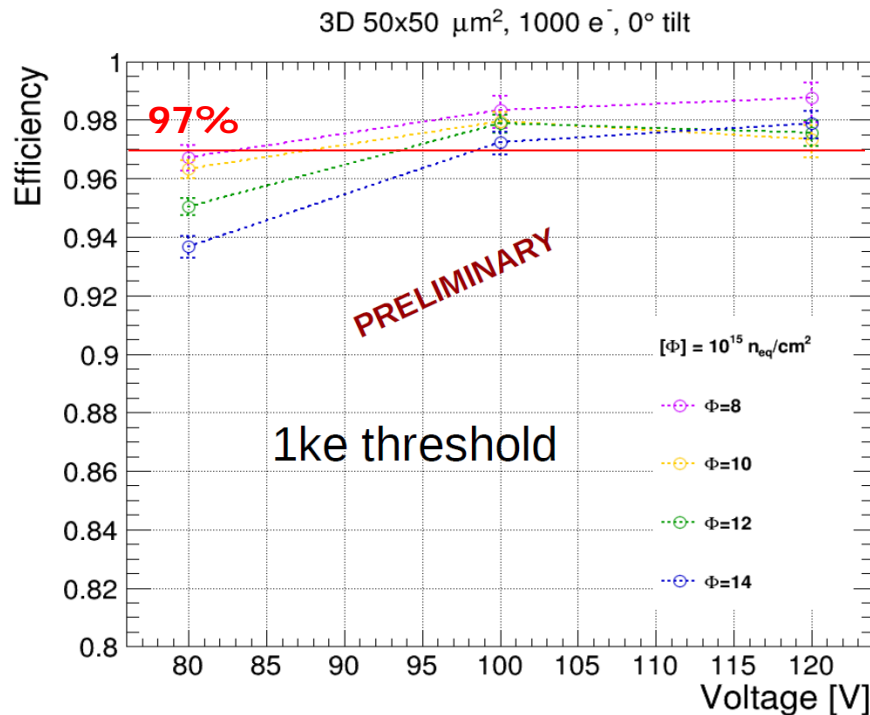


Non-Uniform Irradiation to $1.4 \times 10^{16} \text{ n}_{\text{eq}}/\text{cm}^2$



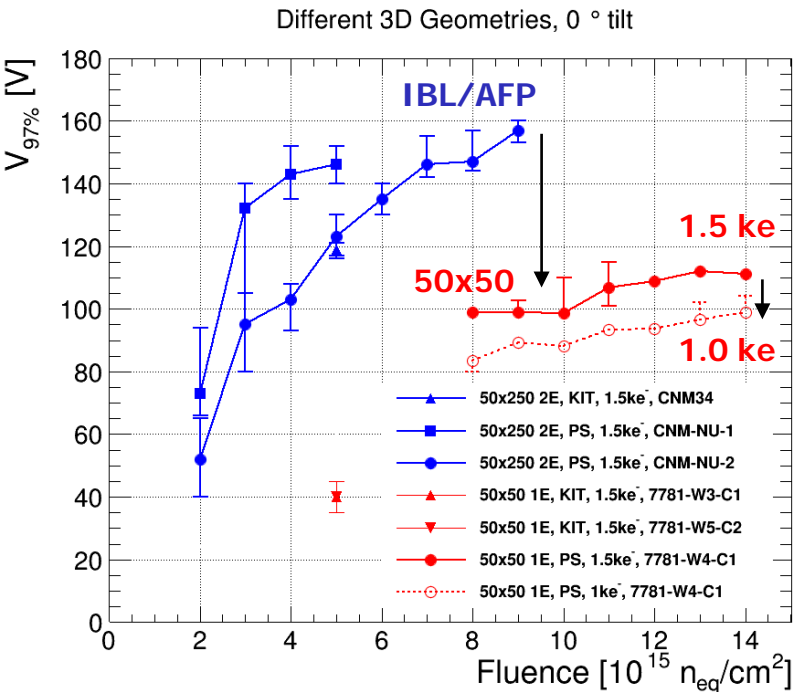
- Non-uniform irradiation at CERN-PS (23 GeV p) with $20 \times 20 \text{ mm}^2$ beam
 - Can sample range of fluences on single device: $0.8 - 1.4 \times 10^{16} \text{ n}_{\text{eq}}/\text{cm}^2$
 - Estimation of systematic fluence uncertainty from variations of beam width and position by 1 mm:
 - 11% at $1.4 \times 10^{16} \text{ n}_{\text{eq}}/\text{cm}^2$
 - 24% at $8 \times 10^{15} \text{ n}_{\text{eq}}/\text{cm}^2$
- Only part of device with connected bumps (bad UBM)
→ Analysis in localised region

Efficiency for Non-Uniform Irradiation



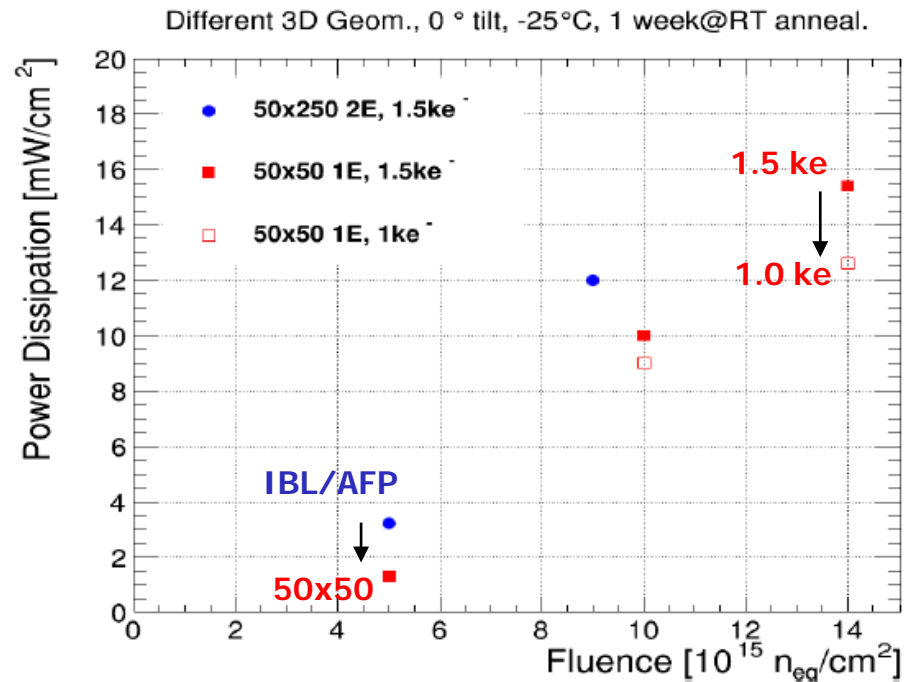
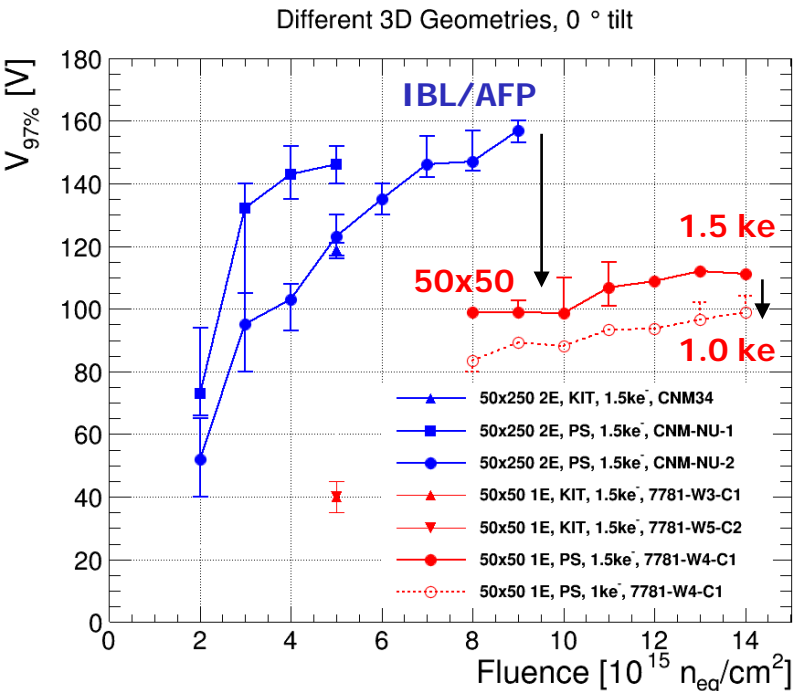
- Efficiency improves with lower threshold
- 97% efficiency already at 100 V (1 ke threshold) after $1.4 \times 10^{16} \text{ n}_{\text{eq}}/\text{cm}^2$!

Comparison IBL to Small Pitch



- Highly improved operation voltage for 50x50 μm^2 3D compared to IBL/AFP generation

Comparison IBL to Small Pitch



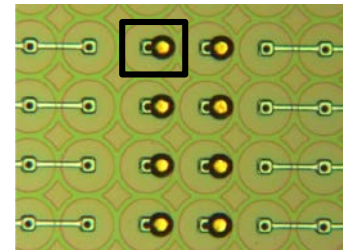
- **Highly improved operation voltage** for 50x50 μm^2 3D compared to IBL/AFP generation
- **Also improves power dissipation**
 - Despite higher current for 50x50 μm^2 (still under investigation, might improve after optimisations)
 - 9 (13) mW/cm² at 1e16 (1.4e16) n_{eq}/cm^2
 - Considerably lower than for 100 μm planar devices* with ≥ 25 mW/cm² at 1e16 n_{eq}/cm^2 ($V_{op}=500$ V)

* N. Savic et al., 28th RD50 Workshop, Torino, Italy, 6-8 June 2016

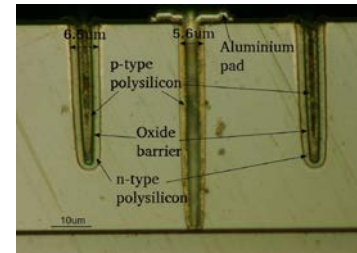
Conclusions and Outlook

- Studied IBL/AFP-generation 3D pixel detectors up to HL-LHC fluences
 - Already excellent radiation hardness
- Studied first CNM 3D production with small HL-LHC pixel size
 - 50x50 and 25x100 μm^2 matched to FEI4 chip
 - Highly reduced operational voltage and power dissipation wrt. IBL/AFP generation (and planar) also after irradiation
 - 100 V for $1.4 \times 10^{16} \text{ n}_{\text{eq}}/\text{cm}^2$
 - Irradiation to higher fluences of $2\text{-}3 \times 10^{16} \text{ n}_{\text{eq}}/\text{cm}^2$ on-going
- Also productions and promising results from FBK and SINTEF
- Single-sided thin (72-150 μm) 3D productions under way at CNM
 - Also with RD53 geometry

50x50 μm^2



See talk by M. Meschini



3D sensors excellent candidates for innermost pixel layer(s) at HL-LHC!

BACKUP
